











TL081, TL081A, TL081B, TL082, TL082A TL082B, TL084, TL084A, TL084B

SLOS081I-FEBRUARY 1977-REVISED MAY 2015

TL08xx JFET-Input Operational Amplifiers

1 Features

- Low Power Consumption: 1.4 mA/ch Typical
- Wide Common-Mode and Differential Voltage Ranges
- Low Input Bias Current: 30 pA Typical
- · Low Input Offset Current: 5 pA Typical
- · Output Short-Circuit Protection
- Low Total Harmonic Distortion: 0.003% Typical
- · High Input Impedance: JFET Input Stage
- · Latch-Up-Free Operation
- High Slew Rate: 13 V/µs Typical
- Common-Mode Input Voltage Range Includes V_{CC+}

2 Applications

- Tablets
- White goods
- · Personal electronics
- Computers

3 Description

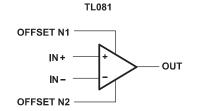
The TL08xx JFET-input operational amplifier family is designed to offer a wider selection than any previously developed operational amplifier family. Each of these JFET-input operational amplifiers incorporates well-matched, high-voltage JFET and bipolar transistors in a monolithic integrated circuit. The devices feature high slew rates, low input bias and offset currents, and low offset-voltage temperature coefficient.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TL084xD	SOIC (14)	8.65 mm × 3.91 mm
TL08xxFK	LCCC (20)	8.89 mm × 8.89 mm
TL084xJ	CDIP (14)	19.56 mm × 6.92 mm
TL084xN	PDIP (14)	19.3 mm × 6.35 mm
TL084xNS	SO (14)	10.3 mm × 5.3 mm
TL084xPW	TSSOP (14)	5.0 mm × 4.4 mm

For all available packages, see the orderable addendum at the end of the data sheet.

Schematic Symbol



TL082 (EACH AMPLIFIER) TL084 (EACH AMPLIFIER)

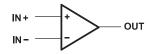




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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

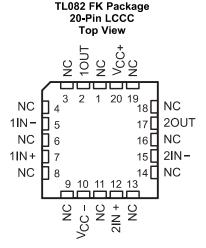
Changes from Revision H (January 2014) to Revision I Added Pin Configuration and Functions section, Storage Conditions table, ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section Added Applications

Changes from Revision G (September 2004) to Revision H • Updated document to new TI data sheet format - no specification changes. • Deleted Ordering Information table.

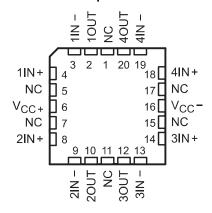
Moved Typical Characteristics into Specifications section. 9



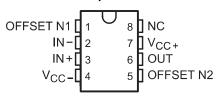
5 Pin Configuration and Functions



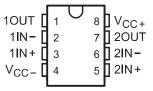
TL084 FK Package 20-Pin LCCC Top View



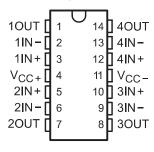
TL081 and TL081x D, P, and PS Package 8-Pin SOIC, PDIP, and SO Top View



TL082 and TL082x D, JG, P, PS and PW Package 8-Pin SOIC, CDIP, PDIP, SO, and TSSOP Top View



TL084 and TL084x D, J, N, NS and PW Package 14-Pin SOIC, CDIP, PDIP, SO, and TSSOP Top View



Pin Functions

		PII	V				
	TL081	TLO	082	TL	084		
NAME	SOIC, PDIP, SO	SOIC, CDIP, PDIP, SO, TSSOP	LCCC	SOIC, CDIP, PDIP, SO, TSSOP	LCCC	I/O	DESCRIPTION
1IN-		2	5	2	3	I	Negative input
1IN+		3	7	3	4	I	Positive input
10UT	_	1	2	1	2	0	Output
2IN-	_	6	15	6	9	I	Negative input
2IN+	_	5	12	5	8	I	Positive input
2OUT	_	7	17	7	10	0	Output
3IN-	_	_	_	9	13	I	Negative input
3IN+	_	_	_	10	14	I	Positive input
3OUT		_	_	8	12	0	Output
4IN-	_	_	_	13	19	I	Negative input
4IN+		_	_	12	18	I	Positive input
4OUT	_	_	_	14	20	0	Output



Pin Functions (continued)

		PII	N						
	TL081	TLO	082	TL	.084				
NAME	SOIC, PDIP, SO	SOIC, CDIP, PDIP, SO, TSSOP	LCCC	SOIC, CDIP, PDIP, SO, TSSOP	LCCC	I/O	DESCRIPTION		
IN-	2	_	_	_	_	I	Negative input		
IN+	3	_		_		I	Positive input		
			1 3		1				
		_	4 6		5	_			
NC	8		8 9	_	7		Do not connect		
			11 13		11				
			14 16		15				
			18	-	17				
OFFSET N1	1	_	_	_	_	_	Input offset adjustment		
OFFSET N2	5	_	_	_	_	_	Input offset adjustment		
OUT	6	_	1	_	1	0	Output		
V _{CC} -	4	4	10	11	16	_	Power supply		
V _{CC+}	7	8	20	4	6	_	Power supply		



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

				MIN	MAX	UNIT		
V _{CC+}	Q				18			
V _{CC}	Supply voltage ⁽²⁾				-18	V		
V _{ID}	Differential input voltage ⁽³⁾				±30	V		
VI	Input voltage ⁽²⁾⁽⁴⁾				±15			
	Duration of output short circuit ⁽⁵⁾			Unlimited				
	Continuous total power dissipation			See Dissipation Rati	ing Table			
			TL08_C TL08_AC TL08_BC	0	70			
T_A	Operating free-air temperature		TL08_I	-40	85	°C		
			TL084Q	-4 0	125			
			TL08_M	– 55	125			
	Operating virtual junction temperat	ure			150	°C		
T _C	Case temperature for 60 seconds	FK package	TL08_M		260	°C		
	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	J or JG package	TL08_M		300	°C		
T _{stg}	Storage temperature			– 65	150	°C		

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) All voltage values, except differential voltages, are with respect to the midpoint between V_{CC+} and V_{CC-}.
- (3) Differential voltages are at IN+, with respect to IN-.
- (4) The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 15 V, whichever is less.
- (5) The output may be shorted to ground or to either supply. Temperature and/or supply voltages must be limited to ensure that the dissipation rating is not exceeded.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	1000	
V _(ESD)	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	1500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC+}	Supply voltage		5	15	V
V _{CC} _	Supply voltage		– 5	– 15	V
V_{CM}	Common-mode voltage		V _{CC} _ + 4	V _{CC+} – 4	V
	y Common-mode voltage	TL08xM	– 55	125	
_	A mala i a mali da malin a malin ma	TL08xQ	-4 0	125	°C
T _A	Ambient temperature	TL08xI	-40	85	C
		TL08xC	0	70	

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

ISTRUMENTS

6.4 Thermal Information

			TL08xx								
		D (SOIC)		N (PDIP)	NS (SO) P (PDIP)		PS (SO)	PW (TSSOP)			
	THERMAL METRIC (1)	8 PINS	14 PINS	14 PINS	14 PINS	{PIN COUNT} PINS	{PIN COUNT} PINS	8 PINS	14 PINS	UNIT	
R _{θJA}	Junction-to-ambient thermal resistance (2)(3)	97	86	76	80	85	95	149	113	°C/W	

- (1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.
- Maximum power dissipation is a function of $T_{J(max)}$, $R_{\theta JA}$, and T_A . The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_{J(max)} T_A) / R_{\theta JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability. The package thermal impedance is calculated in accordance with JESD 51-7.

6.5 Electrical Characteristics for TL08xC, TL08xxC, and TL08xI

 $V_{CC\pm}$ = ±15 V (unless otherwise noted)

PA	RAMETER	TEST	T _A ⁽¹⁾		1C, TL08 TL084C	82C,		AC, TL08			BC, TL08 L084BC			81I, TL08 TL084I	B2I,	UNIT
		CONDITIONS		MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
	Input offset	V = 0	25°C		3	15		3	6		2	3		3	6	
V _{IO}	voltage	$V_O = 0$, $R_S = 50 \Omega$	Full range			20			7.5			5			9	mV
α _{VIO}	Temperature coefficient of input offset voltage	$V_O = 0$, $R_S = 50 \Omega$	Full range		18			18			18			18		μV/°C
	Input offset		25°C		5	200		5	100		5	100		5	100	pA
I _{IO}	current ⁽²⁾	V _O = 0	Full range			2			2			2			10	nA
	Input bias		25°C		30	400		30	200		30	200		30	200	pА
I _{IB}	current ⁽²⁾	V _O = 0	Full range			10			7			7			20	nA
V _{ICR}	Common- mode input voltage range		25°C	±11	–12 to 15		±11	–12 to 15		±11	–12 to 15		±11	–12 to 15		V
	Maximum	R _L = 10 kΩ	25°C	±12	±13.5		±12	±13.5		±12	±13.5		±12	±13.5		
V_{OM}	peak output	R _L ≥ 10 kΩ	Full	±12			±12			±12			±12			V
O.W	voltage swing	R _L ≥ 2 kΩ	range	±10	±12		±10	±12		±10	±12		±10	±12		
	Large-signal		25°C	25	200		50	200		50	200		50	200		
A _{VD}	differential voltage amplification	$V_O = \pm 10 \text{ V},$ $R_L \ge 2 \text{ k}\Omega$	Full range	15			15			25			25			V/mV
B ₁	Unity-gain bandwidth		25°C		3			3			3			3		MHz
r _i	Input resistance		25°C		10 ¹²			10 ¹²			10 ¹²			10 ¹²		Ω
CMRR	Common- mode rejection ratio	$V_{IC} = V_{ICR}min,$ $V_O = 0,$ $R_S = 50 \Omega$	25°C	70	86		75	86		75	86		75	86		dB
k _{SVR}	Supply- voltage rejection ratio (ΔV _{CC±} /ΔV _{IO})	$V_{CC} = \pm 15 \text{ V to}$ $\pm 9 \text{ V},$ $V_{O} = 0,$ $R_{S} = 50 \Omega$	25°C	70	86		80	86		80	86		80	86		dB

⁽¹⁾ All characteristics are measured under open-loop conditions with zero common-mode voltage, unless otherwise specified. Full range for T_A is 0°C to 70°C for TL08_C, TL08_AC, TL08_BC and -40°C to 85°C for TL08_I.

Input bias currents of an FET-input operational amplifier are normal junction reverse currents, which are temperature sensitive, as shown in Figure 13. Pulse techniques must be used that maintain the junction temperature as close to the ambient temperature as possible.



Electrical Characteristics for TL08xC, TL08xxC, and TL08xI (continued)

 $V_{CC\pm}$ = ±15 V (unless otherwise noted)

PAR	RAMETER	TEST CONDITIONS TA(1)		TL081C, TL082C, TL084C		TL081AC, TL082AC, TL084AC		TL081BC, TL082BC, TL084BC			TL081I, TL082I, TL084I			UNIT		
				MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
I _{CC}	Supply current (each amplifier)	V _O = 0, No load	25°C		1.4	2.8		1.4	2.8		1.4	2.8		1.4	2.8	mA
V _{O1} /V _{O2}	Crosstalk attenuation	A _{VD} = 100	25°C		120			120			120			120		dB

6.6 Electrical Characteristics for TL08xM and TL084x

 V_{CC+} = ±15 V (unless otherwise noted)

	DADAMETED	TEST CONDITIONS (1)		TLO	081M, TL082	M	TL0	84Q, TL08	4M	LINUT
	PARAMETER	TEST CONDITIONS ⁽¹⁾	T _A	MIN	TYP	MAX	MIN	TYP	MAX	UNIT
	land effect cells	V = 0 D = 50 O	25°C		3	6		3	9	\/
V _{IO}	Input offset voltage	$V_{\rm O} = 0$, $R_{\rm S} = 50 \ \Omega$	Full range			9			15	mV
α _{VIO}	Temperature coefficient of input offset voltage	$V_{O} = 0, R_{S} = 50 \Omega$	Full range		18			18		μV/°C
	Input offset current ⁽²⁾	V _O = 0	25°C		5	100		5	100	pА
I _{IO}	input onset current	V _O = 0	125°C			20			20	nA
			25°C		30	200		30	200	pА
I _{IB}	Input bias current ⁽²⁾	V _O = 0	125°C			50			50	nA
V _{ICR}	Common-mode input voltage range		25°C	±11	–12 to 15		±11	–12 to 15		V
		R _L = 10 kΩ	25°C	±12	±13.5		±12	±13.5		
V_{OM}	Maximum peak output voltage swing	R _L ≥ 10 kΩ	E. II. and and	±12			±12			V
	output voltage swing	$R_L \ge 2 k\Omega$	Full range	±10	±12		±10	±12		
	Large-signal differential	V .40 V D > 0 LO	25°C	25	200		25	200) (/) (
A_{VD}	voltage amplification	$V_O = \pm 10 \text{ V}, R_L \ge 2 \text{ k}\Omega$	Full range	15			15			V/mV
B ₁	Unity-gain bandwidth		25°C		3			3		MHz
r _i	Input resistance		25°C		10 ¹²			10 ¹²		Ω
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}min,$ $V_O = 0, R_S = 50 \Omega$	25°C	80	86		80	86		dB
k _{svr}	Supply-voltage rejection ratio (ΔV _{CC±} /ΔV _{IO})	$V_{CC} = \pm 15 \text{ V to } \pm 9 \text{ V},$ $V_{O} = 0, R_{S} = 50 \Omega$	25°C	80	86		80	86		dB
I _{cc}	Supply current (each amplifier)	V _O = 0, No load	25°C		1.4	2.8		1.4	2.8	mA
V _{O1} /V _{O2}	Crosstalk attenuation	A _{VD} = 100	25°C		120			120		dB

⁽¹⁾ All characteristics are measured under open-loop conditions, with zero common-mode input voltage, unless otherwise specified.

6.7 Operating Characteristics

 $V_{CC+} = \pm 15 \text{ V}, T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		$V_I = 10 \text{ V}, R_L = 2 \text{ k}\Omega, C_L = 100 \text{ pF},$ See Figure 19	8 ⁽¹⁾	13		
SR	Slew rate at unity gain	$V_I = 10 \text{ V}, R_L = 2 \text{ k}\Omega, C_L = 100 \text{ pF},$ $T_A = -55^{\circ}\text{C}$ to 125°C, See Figure 19	5 ⁽¹⁾			V/µs

(1) On products compliant to MIL-PRF-38535, this parameter is not production tested.

⁽²⁾ Input bias currents of a FET-input operational amplifier are normal junction reverse currents, which are temperature sensitive, as shown in Figure 13. Pulse techniques must be used that maintain the junction temperatures as close to the ambient temperature as possible.



Operating Characteristics (continued)

 $V_{CC\pm}$ = ±15 V, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _r	Rise-time	$V_{I} = 20 \text{ V}, R_{I} = 2 \text{ k}\Omega,$	C _I = 100 pF,		0.05		μs
	overshoot factor	See Figure 19			20%		
V _n	Equivalent input noise voltage	R _S = 20 Ω	f = 1 kHz		18		nV/√ Hz
			f = 10 Hz to 10 kHz		4		μV
I n	Equivalent input noise current	$R_S = 20 \Omega$,	f = 1 kHz		0.01		pA/√ Hz
THD	Total harmonic distortion	V_I rms = 6 V, A_{VD} = 1, $R_S \le$ 1 k Ω , $R_L \ge$ 2 k Ω , f = 1 kHz,			0.003%		

6.8 Dissipation Rating Table

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR	DERATE ABOVE T _A	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
D (14 pin)	680 mW	7.6 mW/°C	60°C	604 m/W	490 mW	186 mW
FK	680 mW	11.0 mW/°C	88°C	680 m/W	680 mW	273 mW
J	680 mW	11.0 mW/°C	88°C	680 m/W	680 mW	273 mW
JG	680 mW	8.4 mW/°C	69°C	672 m/W	546 mW	210 mW

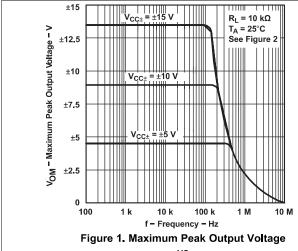


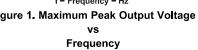
6.9 Typical Characteristics

Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices. The Figure numbers referenced in the following graphs are located in Parameter Measurement Information.

Table 1. Table of Graphs

			Figure
V _{OM}	Maximum peak output voltage	versus Frequency versus Free-air temperature versus Load resistance versus Supply voltage	Figure 1, Figure 2, Figure 3 Figure 4 Figure 5 Figure 6
	Large-signal differential voltage amplification	versus Free-air temperature versus Load resistance	Figure 7 Figure 8
A _{VD}	Differential voltage amplification	versus Frequency with feed-forward compensation	Figure 9
P _D	Total power dissipation	versus Free-air temperature	Figure 10
I _{CC}	Supply current	versus Free-air temperature versus Supply voltage	Figure 11 Figure 12
I _{IB}	Input bias current	versus Free-air temperature	Figure 13
	Large-signal pulse response	versus Time	Figure 14
Vo	Output voltage	versus Elapsed time	Figure 15
CMRR	Common-mode rejection ratio	versus Free-air temperature	Figure 16
V _n	Equivalent input noise voltage	versus Frequency	Figure 17
THD	Total harmonic distortion	versus Frequency	Figure 18





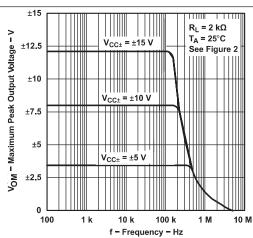
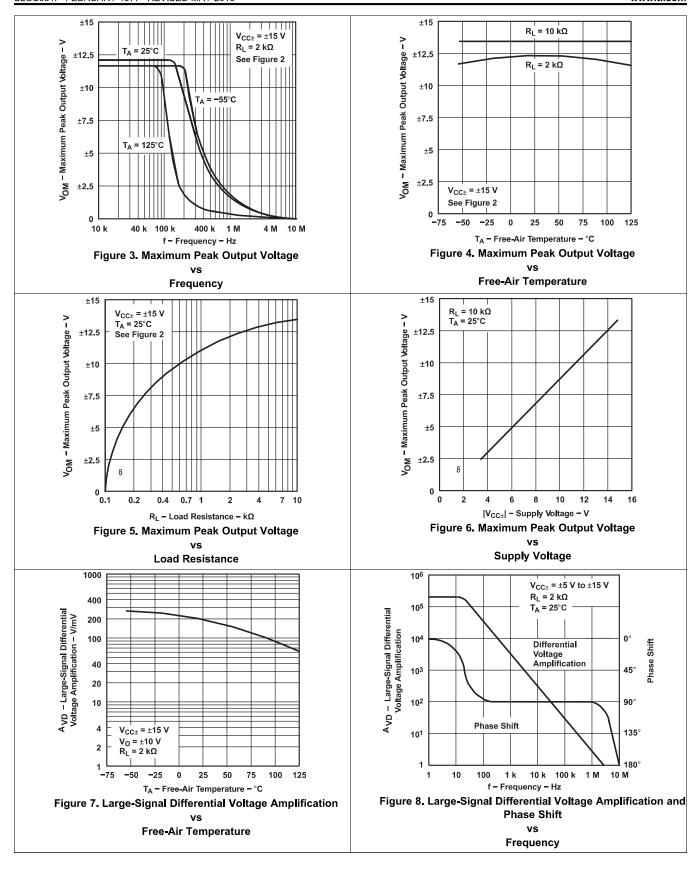
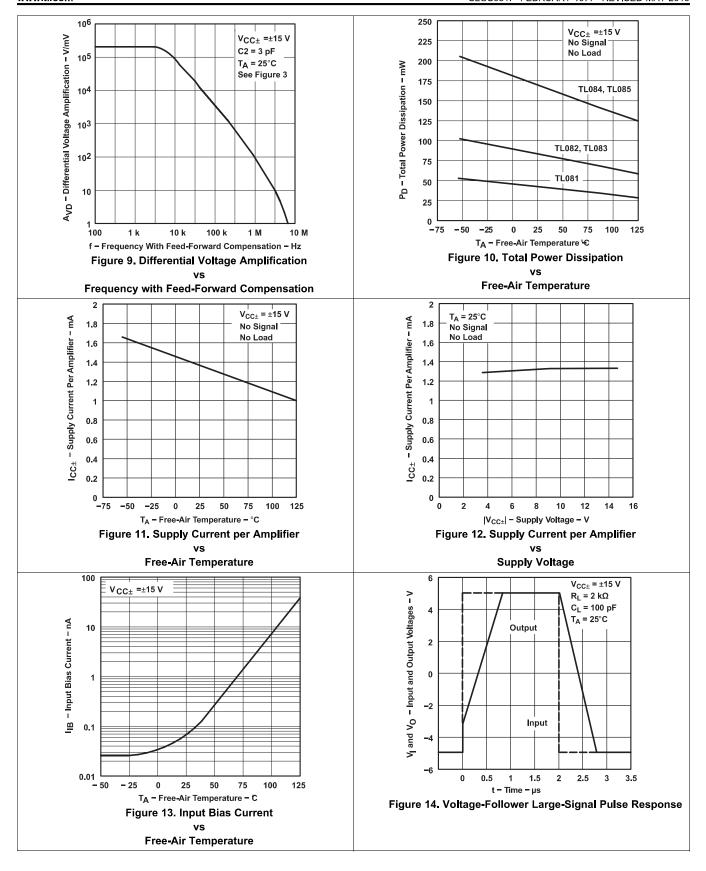


Figure 2. Maximum Peak Output Voltage Frequency

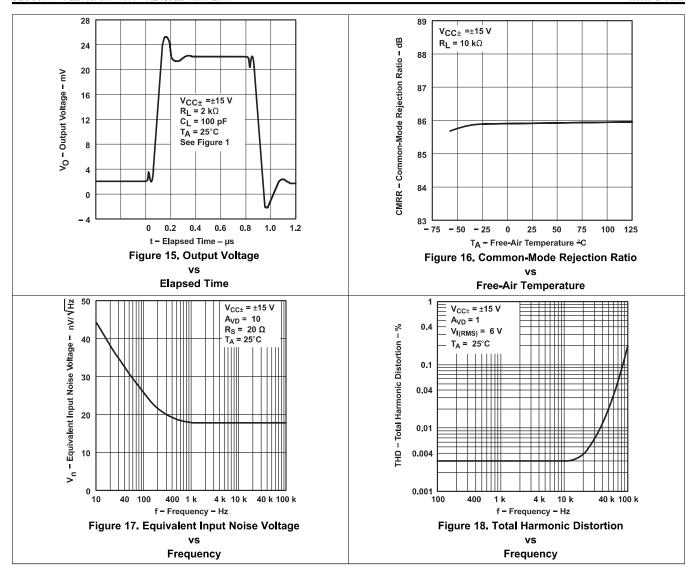














7 Parameter Measurement Information

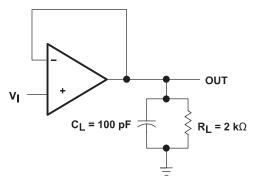


Figure 19. Test Figure 1

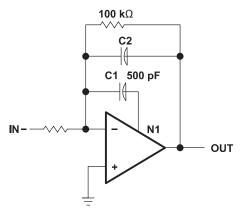


Figure 21. Test Figure 3

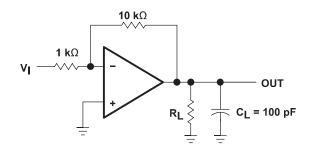


Figure 20. Test Figure 2

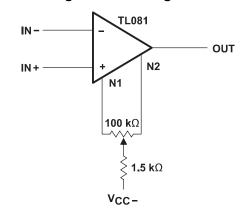


Figure 22. Test Figure 4



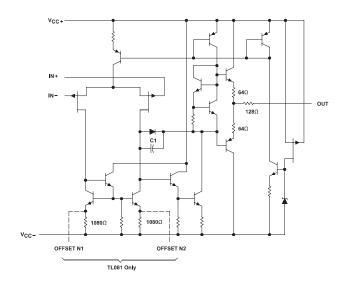
8 Detailed Description

8.1 Overview

The TL08xx JFET-input operational amplifier family is designed to offer a wider selection than any previously developed operational amplifier family. Each of these JFET-input operational amplifiers incorporates well-matched, high-voltage JFET and bipolar transistors in a monolithic integrated circuit. The devices feature high slew rates, low input bias and offset currents, and low offset-voltage temperature coefficient. Offset adjustment and external compensation options are available within the TL08xx family.

The C-suffix devices are characterized for operation from 0°C to 70°C. The I-suffix devices are characterized for operation from −40°C to 85°C. The Q-suffix devices are characterized for operation from −40°C to +125°C. The M-suffix devices are characterized for operation over the full military temperature range of −55°C to +125°C.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Total Harmonic Distortion

Harmonic distortions to an audio signal are created by electronic components in a circuit. Total harmonic distortion (THD) is a measure of harmonic distortions accumulated by a signal in an audio system. These devices have a very low THD of 0.003% meaning that the TL08x devices will add little harmonic distortion when used in audio signal applications.

8.3.2 Slew Rate

The slew rate is the rate at which an operational amplifier can change its output when there is a change on the input. These devices have a 13-V/µs slew rate.

8.4 Device Functional Modes

These devices are powered on when the supply is connected. This device can be operated as a single-supply operational amplifier or dual-supply amplifier depending on the application.



9 Applications and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TL08x series of operational amplifiers can be used in countless applications. The few applications in this section show principles used in all applications of these parts.

9.2 Typical Applications

9.2.1 Inverting Amplifier Application

A typical application for an operational amplifier in an inverting amplifier. This amplifier takes a positive voltage on the input, and makes it a negative voltage of the same magnitude. In the same manner, it also makes negative voltages positive.

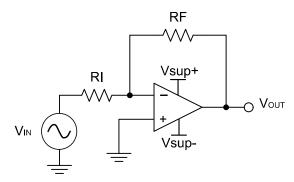


Figure 23. Schematic for Inverting Amplifier Application

9.2.1.1 Design Requirements

The supply voltage must be chosen such that it is larger than the input voltage range and output range. For instance, this application will scale a signal of ± 0.5 V to ± 1.8 V. Setting the supply at ± 12 V is sufficient to accommodate this application.

9.2.1.2 Detailed Design Procedure

Determine the gain required by the inverting amplifier:

$$A_{v} = \frac{VOUT}{VIN} \tag{1}$$

$$A_v = \frac{1.8}{-0.5} = -3.6 \tag{2}$$

Once the desired gain is determined, choose a value for RI or RF. Choosing a value in the $k\Omega$ range is desirable because the amplifier circuit will use currents in the milliamp range. This ensures the part will not draw too much current. This example will choose 10 $k\Omega$ for RI which means 36 $k\Omega$ will be used for RF. This was determined by Equation 3.

$$A_{v} = -\frac{RF}{RI} \tag{3}$$

Typical Applications (continued)

9.2.1.3 Application Curve

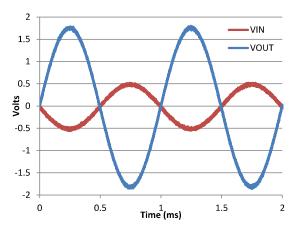


Figure 24. Input and output voltages of the inverting amplifier

9.3 System Examples

9.3.1 General Applications

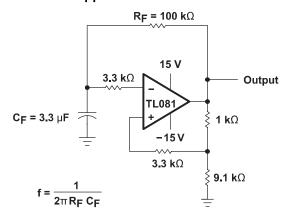


Figure 25. 0.5-Hz Square-Wave Oscillator

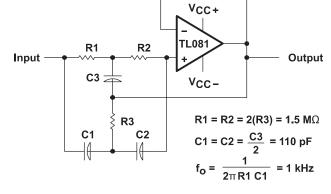


Figure 26. High-Q Notch Filter

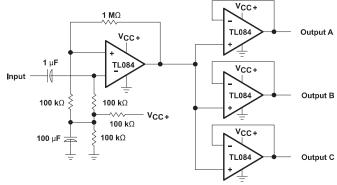
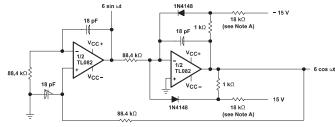


Figure 27. Audio-Distribution Amplifier



A. These resistor values may be adjusted for a symmetrical output.

Figure 28. 100-kHz Quadrature Oscillator



System Examples (continued)

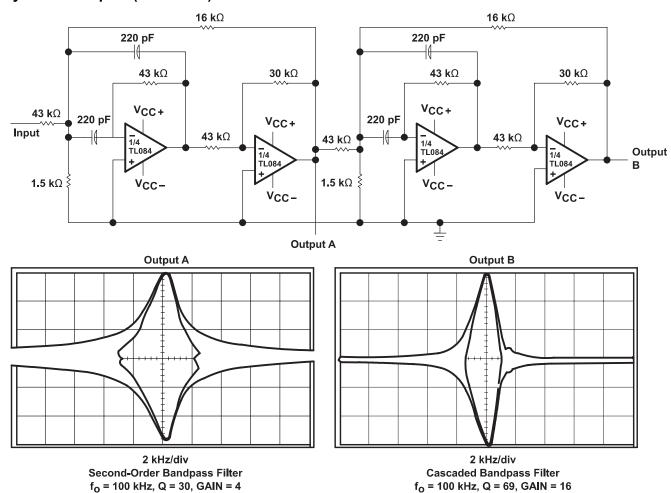


Figure 29. Positive-Feedback Bandpass Filter



10 Power Supply Recommendations

CAUTION

Supply voltages larger than 36 V for a single-supply or outside the range of ± 18 V for a dual-supply can permanently damage the device (see the *Absolute Maximum Ratings*).

Place 0.1-µF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high impedance power supplies. For more detailed information on bypass capacitor placement, refer to the *Layout*.

11 Layout

11.1 Layout Guidelines

For best operational performance of the device, use good PCB layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole, as well as the
 operational amplifier. Bypass capacitors are used to reduce the coupled noise by providing low impedance
 power sources local to the analog circuitry.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of circuitry is one of the simplest and most-effective
 methods of noise suppression. One or more layers on multilayer PCBs are usually devoted to ground planes.
 A ground plane helps distribute heat and reduces EMI noise pickup. Make sure to physically separate digital
 and analog grounds, paying attention to the flow of the ground current. For more detailed information, refer to
 Circuit Board Layout Techniques, (SLOA089).
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If
 it is not possible to keep them separate, it is much better to cross the sensitive trace perpendicular as
 opposed to in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keeping RF and RG close to the inverting input minimizes parasitic capacitance, as shown in *Layout Examples*.
- Keep the length of input traces as short as possible. Always remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.



11.2 Layout Examples

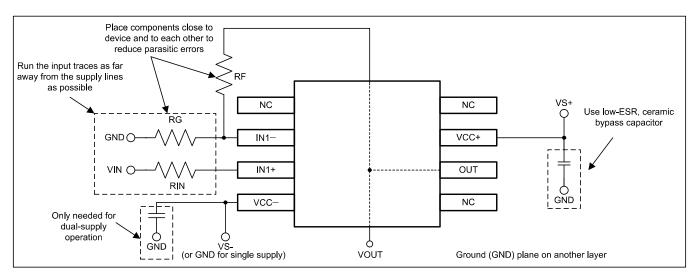


Figure 30. Operational Amplifier Board Layout for Noninverting Configuration

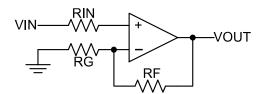


Figure 31. Operational Amplifier Schematic for Noninverting Configuration



Click here

12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For more information, see the following:

Circuit Board Layout Techniques, SLOA089.

12.2 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

TECHNICAL TOOLS & SUPPORT & SAMPLE & BUY PARTS PRODUCT FOLDER **DOCUMENTS** SOFTWARE COMMUNITY TL081 Click here Click here Click here Click here Click here TL081A Click here Click here Click here Click here Click here TL081B Click here Click here Click here Click here Click here TL082 Click here Click here Click here Click here Click here Click here TL082A Click here Click here Click here Click here TL082B Click here Click here Click here Click here Click here TL084 Click here Click here Click here Click here Click here Click here TL084A Click here Click here Click here Click here

Table 2. Related Links

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

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TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

TL084B

E2E is a trademark of Texas Instruments.

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Click here

12.5 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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